Report on DC-DC Converters for HEP and the Role of GaN FETs Why Physics experiments need GaN based DC-DC Converters?

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AIST: Advanced Industrial Science & Technology Center

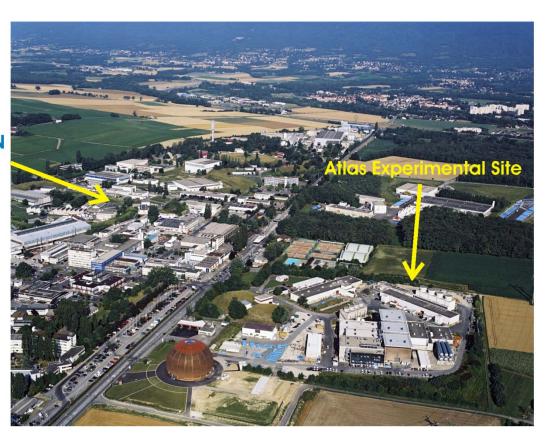
Tsukuba, Japan 3 October 2012,

Agenda

- ❖ Power efficiency issues / problems CMS-ECAL Example
- What can we do?
- Buck Converter commercial Rad Hard Converter
- Noise Tests or Air coils with ATLAS Trackers
- Why need Thin Oxide
- GaN: Radiation Test Results Wide band Gap materials
- ❖ Air Coils from 2000 Present
- GaN companies Why Commercial Interest?
- ❖ MCM Modules Future
- ❖ SiD Detector for ILC 48V > 5V > 1V
- Silicon strip Detector @ Yale for Noise Tests
- Remarks

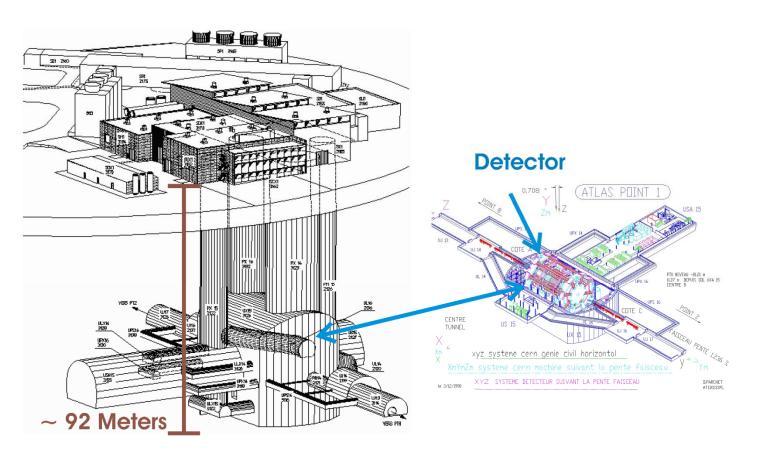
Atlas Experiment

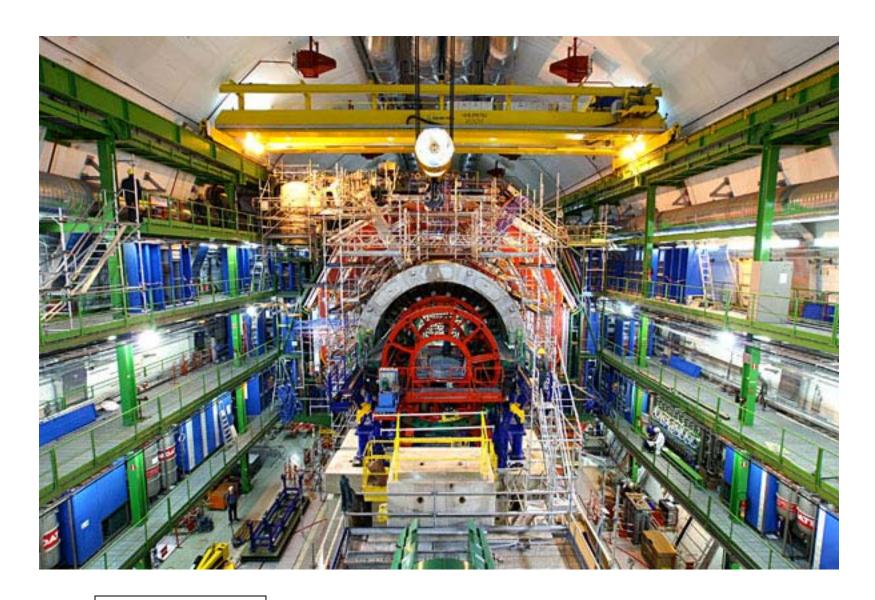
- Collaboration of ~ 1800 physicists from 150 universities and laboratories from 35 countries



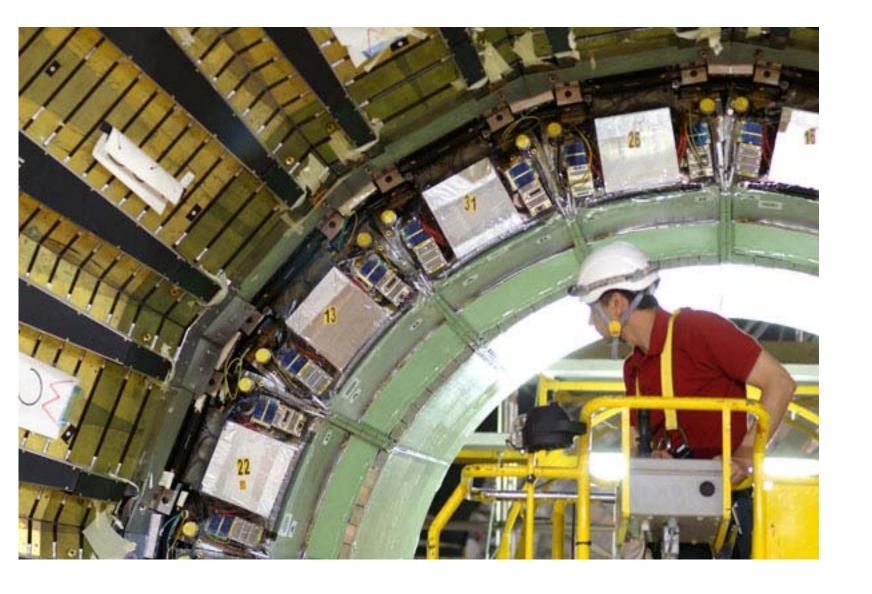
Main CERN Site

Atlas Detector is underground



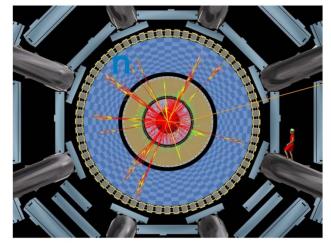


CMS Detector

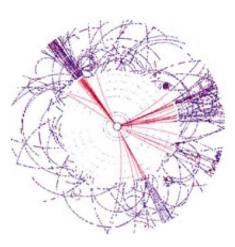


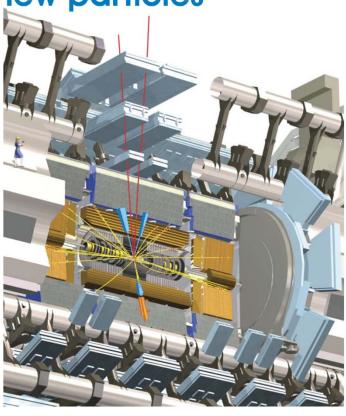
CMS Detector outer detecting elements

Various views of a proton-proton



collision creating many new particles







CMS Outreach

FEET

China

Pakistan



37 Countries, 155 Institutes, 2000 scientists (including about 400 students)

October 2006

PRESHOWER Armenia, CERN, Greece, India, Russia, Taiwan

FORWARD

CALORIMETER

Hungary, Iran, Russia, Turkey, USA

TRIGGER, DATA ACQUISITION & OFFLINE COMPUTING

TRACKER Austria, Belgium, CERN, Finland, France, Germany, Italy, Japan*, Mexico, New Zealand, Switzerland, UK, USA

Austria, Brazil, CERN, Finland, France, Greece, Hungary, Ireland, Italy, Korea, Poland, Portugal, Switzerland, UK, USA CRYSTAL ECAL Belarus, CERN, China, Croatia, Cyprus, France, Italy, Japan*, Portugal, Russia, Serbia, Switzerland, UK, USA RETURN YOKE Barrel: Czech Rep., Estonia, Germany, Greece, Russia Endcap: Japan*, USA SUPERCONDUCTING MAGNET

All countries in CMS contribute to Magnet financing in particular: Finland, France, Italy, Japan*, Korea, Switzerland, USA

Tesla

HCAL.

Barrel: Bulgaria, India, Spain*, USA Endcap: Belarus, Bulgaria, Georgia, Russia,

Ukraine, Uzbekistan

HO: India

Barrel: Austria, Bulgaria, CERN, China,

Germany, Hungary, Italy, Spain,

Endcap: Belarus, Bulgaria, China, Colombia,

Korea, Pakistan, Russia, USA

* Only through industrial contracts

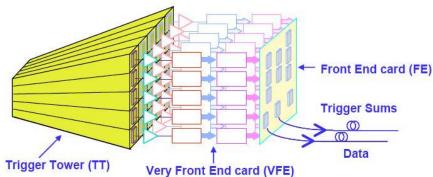
Total weight Overall diameter 12500 T 15.0 m Overall length 21.5 m

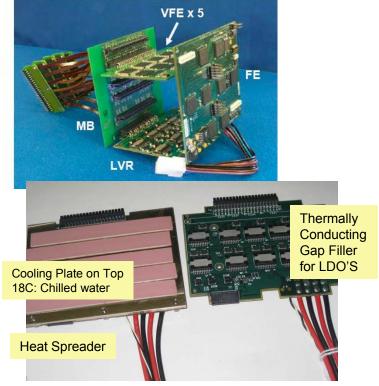
Magnetic field

MUON CHAMBERS

20th Century State of Power Distribution – *LHC Detectors*

ECAL readout system was:
designed in ~2000
produced in 2001-2007
commissioned in 2006-2007





CMS ECAL: 50,000 amps.

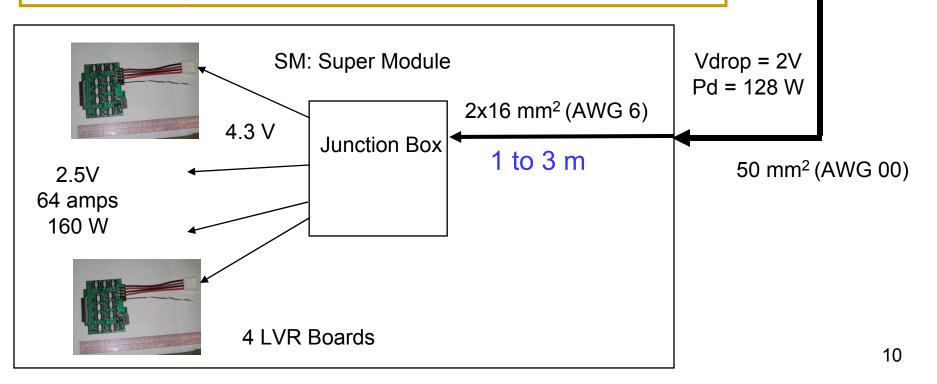
Power Supply 6.3 V

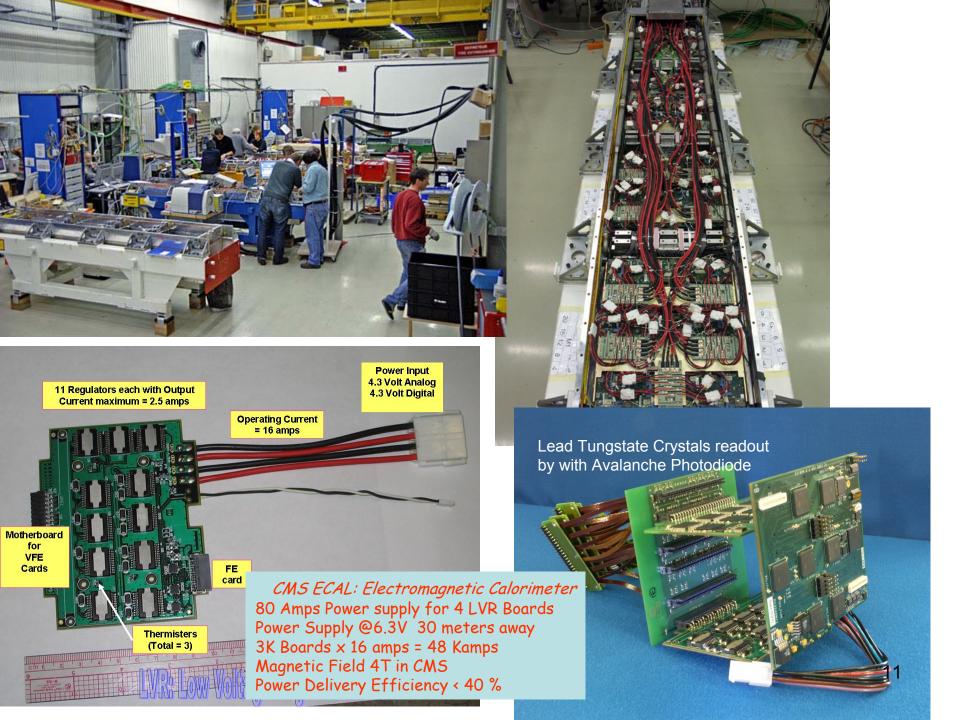
64 Amps

30 m

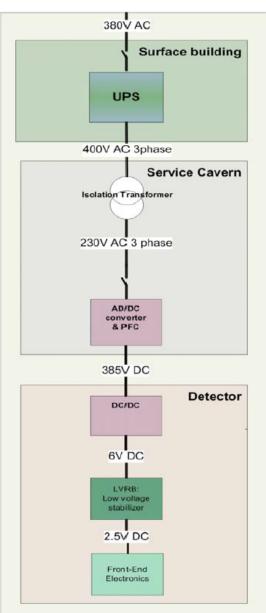
of Power Supplies ~ 700 # of ST LDO Chips = 35 K LHC Radiation Hard made by ST Microelectronics # of LVR Cards = 3.1 K.

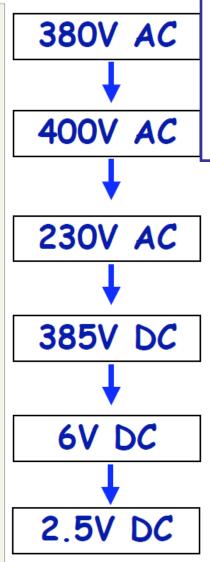
Yale: Designed, built, burn-in and Tested.





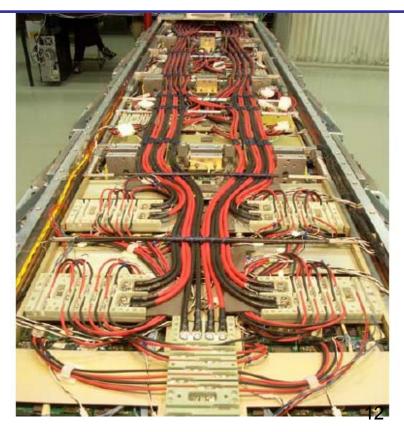
20th Century State of Power Distribution – *LHC Detectors*



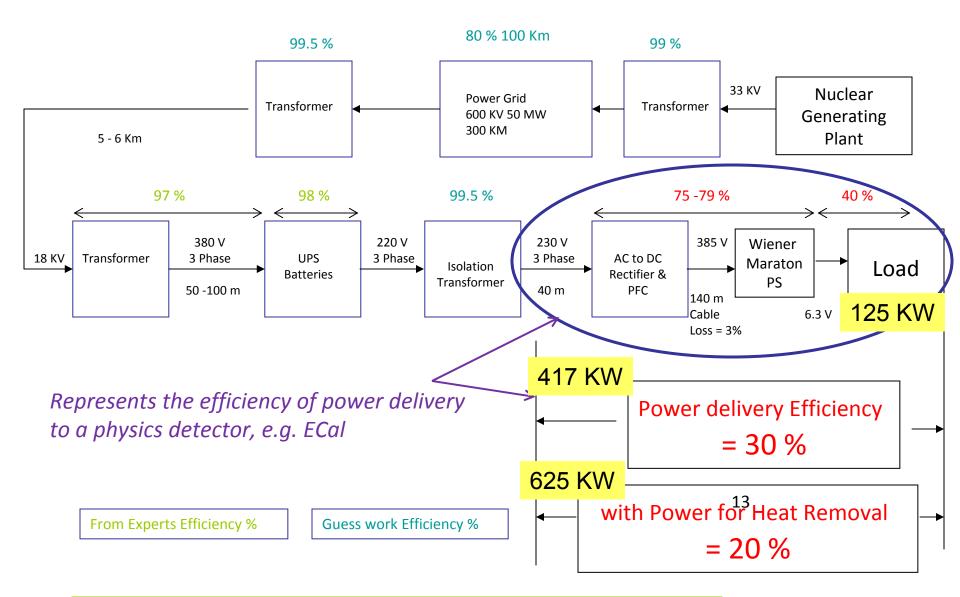


ECAL readout system:

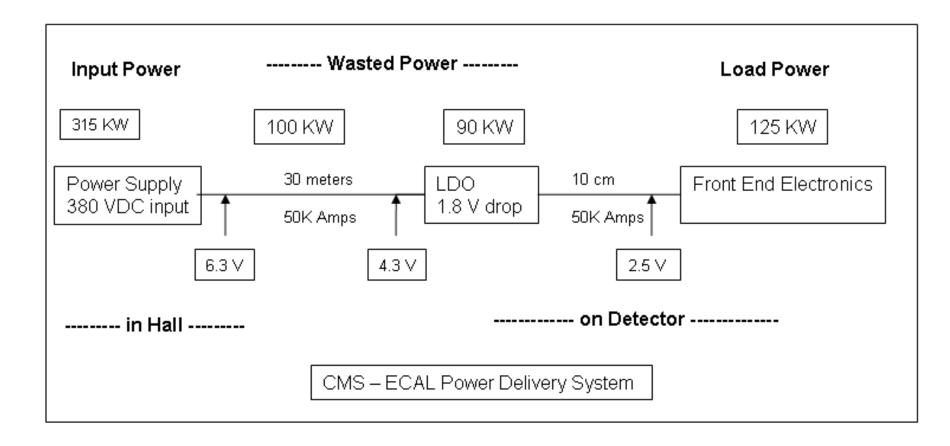
- Concept 1990's
- ❖ designed in ~2000
- produced in 2001-2007
- commissioned in 2006-2007



Power Chain Efficiency for CMS ECAL



Power Efficiency _ Inefficiency _ Wasted Power



CMS Project done, so Funding ended DoE decided Yale change from CMS > ATLAS

STACKS A NOTICE WAY TO BE IVE NOWER'S

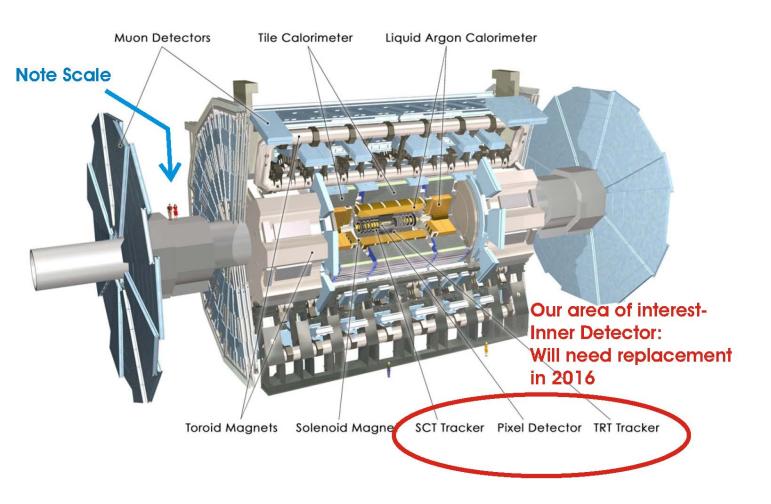
But Need a project, so picked ATLAS Silicon tracker Upgrade with DC-DC. After 2 years management decision use Serial Power instead of DC-DC.

Had small SiD ILC 3 year grant. Winding down.

Spring 2011 CDR&D Proposal with ANL,BNL, Fermilab, SLAC. Reviewers say it is too expensive September 2012: Submitted a smaller 2 year proposal for Air Core Coil developments

Power is difficult, so why waste money - some one will do it?

Atlas Detector Consists of Many Sub-Detectors



Collider Detector Power Essential

Sub-Systems operate:

Magnetic Field: ATLAS = 2 T: CMS = 4 T

: Outside Magnet 0.1 to 1 T at location of power supplies

Radiation Tolerance: Highest for trackers ~ 50 (Strips) 500 (Pixels) Mrads

~ 1 Mrads for outer sub systems

Test with Gammas – Cobalt 60 Source

Protons 800 MeV

Neutrons 1 MeV (Equivalent) from research Nuclear Reactors

Heavy Ions produced here are low energy & do not penetrate IC lids

Electronics Cooling: Chilled Water, Evaporative Cooling – 5C

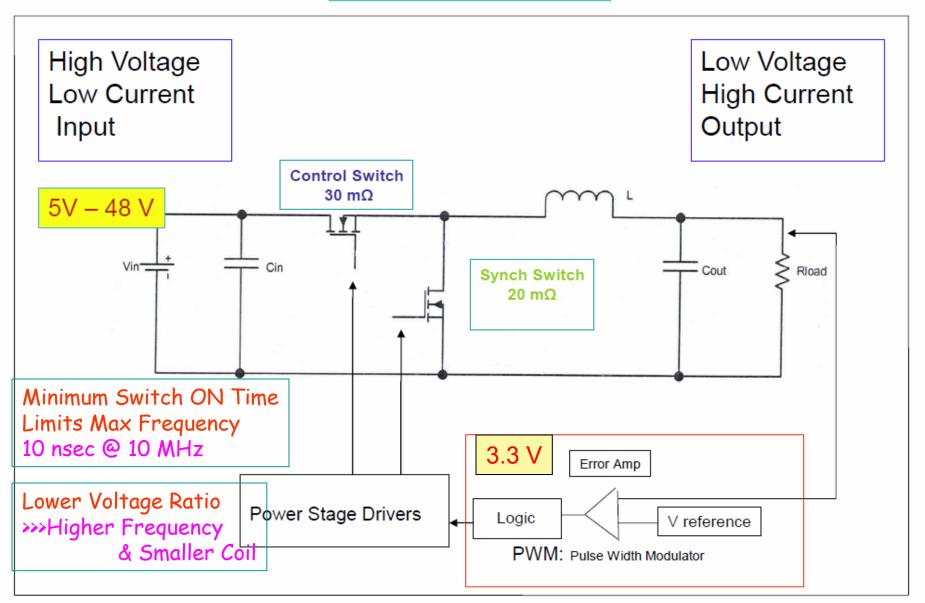
Future Liquid Carbon Dioxide -30C

Wish List

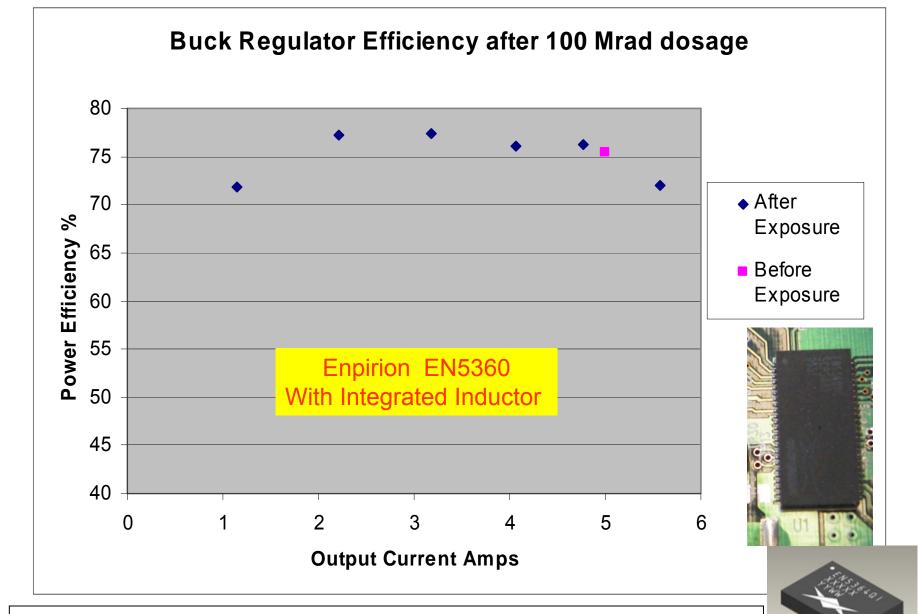
- Buck or Boost Converter.
- ❖ Voltage ratio =10:1 or Higher.
- ❖ 4 Tesla > No magnetic material
- Air Core Inductors
- Radiation Hardness. We had zero experience. Experts advice custom ICs with sub-micron Lithography.

Sander Mos: Zero Iron Power Supply http://www.nikhef.nl/~sanderm/zips/index.html

Buck Converter



Industry: Integrate different technologies, power handling into suitable packages



Found out at Power Technology conference 0.25 µm Lithography

- Irradiated Stopped on St. Valentines Day 2007
- We reported @ TWEPP 2008 IHP was foundry for EN5360

Magnetic Field Effect

7 Tesla Field Chemistry Department Super Conducting Magnet in Persistence Mode

Effect:

Vout = 3.545 Outside

Vout = 3.546 Edge of magnet

Vout = 3.549 Center of magnet

Change= Increased Vout 1 part in 900 at 7T



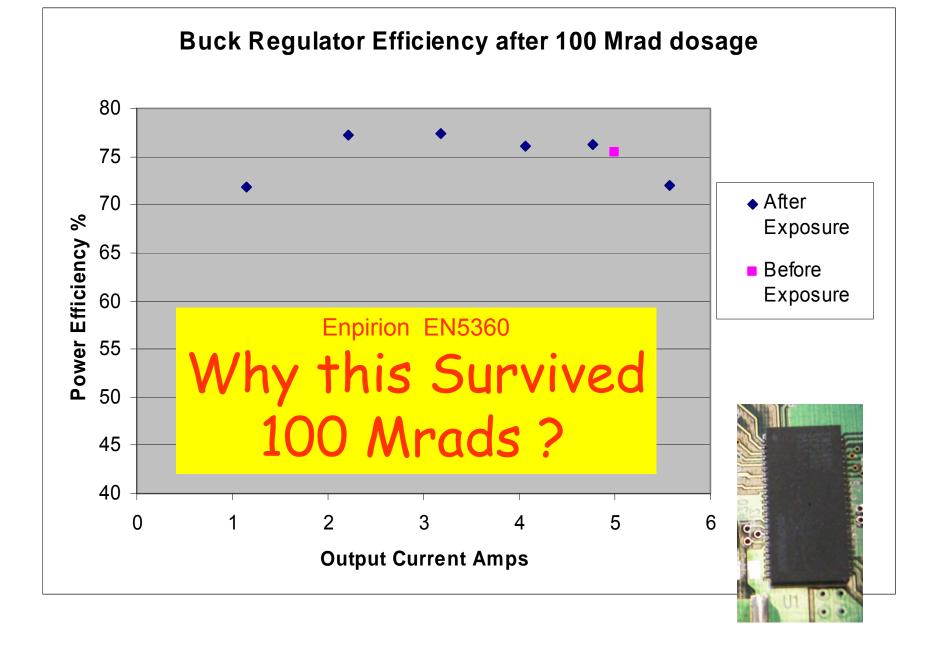
Ionizing Radiation Results – Commercial Converters

Dose rate= 0.2 Mrad/hr

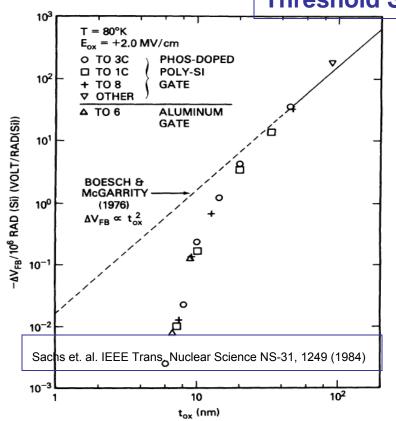
5- 12 nm Gate Oxide

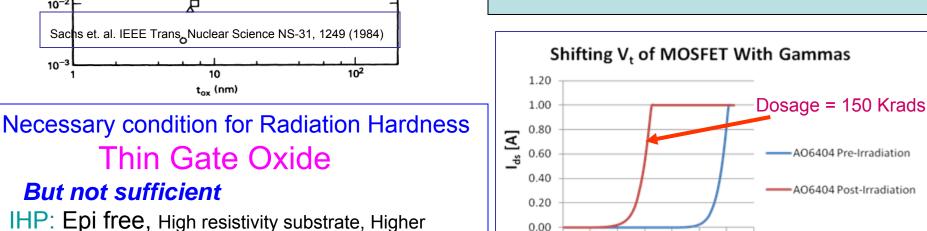
Many more tested but similar failure-Thin oxide converters survive > 200 Krads

| _ | | | | |
|-------------------|--|---|---|---|
| Company | Device | Oxide Thickness (nm) | Dose before Damage | Observation Damage Mode |
| IHP | ASIC | 5 | 53 Mrad | slight damage |
| XYSemi | MOS FET | 7 | 52 Mrad | Minimal damage |
| XYSemi | XP5062 | 12.3 | 44 krad | Loss of output voltage regulation |
| TI | TPS54620 | 20 | 23 krad | abrupt failure |
| Intersil | ISL 8502 | unknow n | 40.6 krad | Increasing input current |
| IR | IR3822 | unknown | 139 krads | Increasing input current |
| IR | IR3841 | 9 & 25 | 13 krads | Loss of output voltage regulation |
| ST | ST1510 | unknown | 125 krad | Loss of output voltage regulation |
| Enpirion | EN5365 | 5 | 85 krad | Increasing input current, |
| Enpirion | EN5382 | 5 | 111 krads | Loss of output voltage regulation |
| Enpirion | EN5360 #2 | 5 | 100 Mrads | No significant Changes |
| Enpirion | EN5360 #3 | 5 | 48 Mrads | No significant changes |
| National Semi. | LM2864 | 11.8 | 3 Mrads | Short after power recycle |
| | XYSemi XYSemi TI Intersil IR IR ST Enpirion Enpirion Enpirion Intersil | XYSemi MOS FET XYSemi XP5062 TI TPS54620 Intersil ISL 8502 IR IR3822 IR IR3841 ST ST1510 Enpirion EN5365 Enpirion EN5382 Enpirion EN5360 #2 Enpirion EN5360 #3 National LM2864 | IHP ASIC 5 XYSemi MOS FET 7 XYSemi XP5062 12.3 TI TPS54620 20 Intersil ISL unknow n IR IR3822 unknown IR IR3841 9 & 25 ST ST1510 unknown Enpirion EN5365 5 Enpirion EN5382 5 Enpirion EN5360 #2 5 National I M2864 11 8 | IHP ASIC 5 53 Mrad XYSemi MOS FET 7 52 Mrad XYSemi XP5062 12.3 44 krad TI TPS54620 20 23 krad Intersil ISL 8502 unknow 40.6 krad IR IR3822 unknown 139 krads IR IR3841 9 & 25 13 krads ST ST1510 unknown 125 krad Enpirion EN5365 5 85 krad Enpirion EN5382 5 111 krads Enpirion EN5360 #2 5 100 Mrads Enpirion EN5360 #3 5 48 Mrads National LM2864 11.8 3 Mrads |



Threshold Shift vs Gate Oxide Thickness

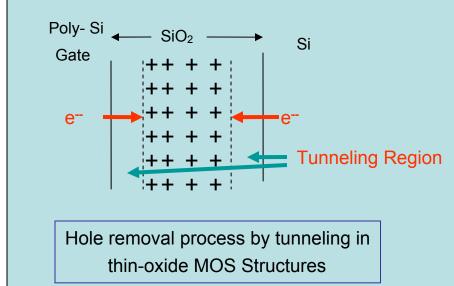




0.00

0.0 0.2 0.4

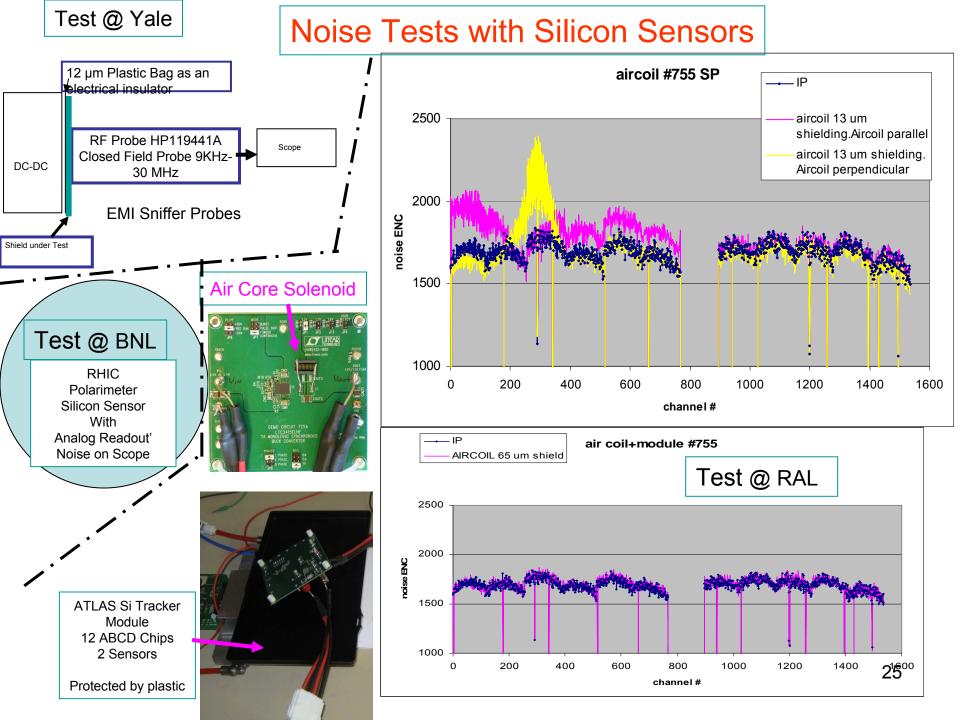
voltage, lower noise devices Dongbu: Epi process on substrate, lower voltage due to hot carriers in gate oxide



24

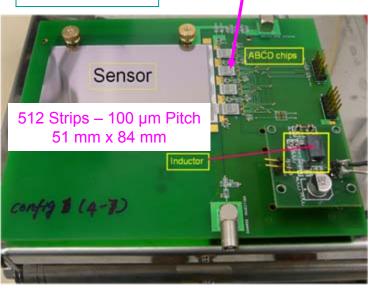
0.6 0.8 1.0 1.2 1.4

V, [V]

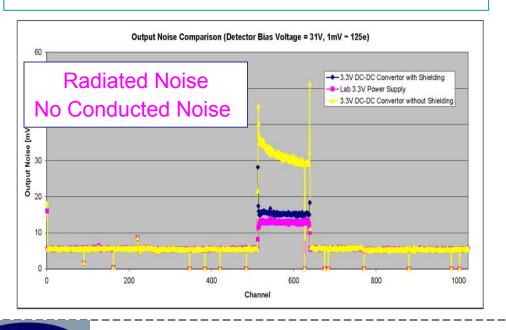


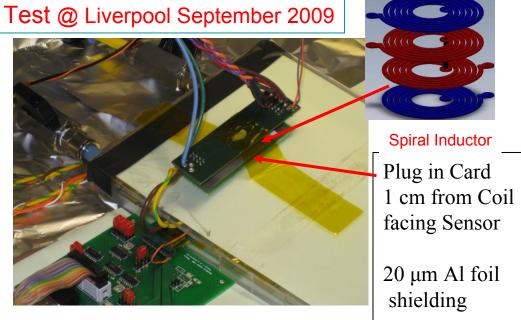
Test @ BNL

Only One Chip Bonded



Noise Tests with Silicon Sensors





| Coil Type | Power | Input Noise electrons rms |
|----------------|------------|---------------------------|
| Solenoid | DC - DC | 881 |
| Solenoid | Linear | 885 |
| | | |
| Spiral Coil | DC - DC | 666 |
| Spiral Coil | Linear | 664 |

Can We Have High Radiation Tolerance & Higher Voltage Together ???

Controller PWM : Low Voltage

High Voltage: Switches -

5- 7 nm Gate Oxide supports 5 V operation

LDMOS, Drain Extension, Field Plates – Reduce Electric Field under Gate (recent work 3 nm > 12 V operating: 7 nm > 70 V power FETs)

>> 20 Volts HEMT GaN on Silicon, Silicon Carbide, Sapphire



Wide Band Gap Materials

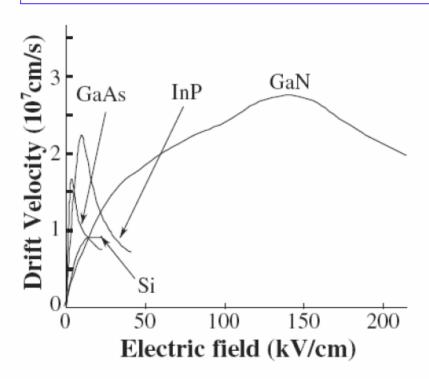


Fig. 8. Dependence of drift velocity of semiconductors on electric field. GaAs and InP have high mobilities (slope of drift velocity-electric field relation in the low-electric-field region); however, their drift velocities decrease in the high-electric-field region. On the other hand, GaN shows high drift velocity in the high-electric-field region.

Radiation Results – RF GaN & EPC GaN on Si

Nitronex 25015 5 x 10¹⁴ Neutrons/cm²

Eudyna EGNB010, SN243 Before and After ⁶⁰Co Radiation

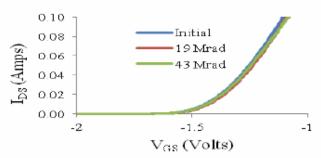


Fig. 7. Eudyna EGNB010 GaN HEMT, VGS versus IDS at VDS = 10 volts and selected doses of 60Co gamma radiation. Little change is apparent even after 43 Mrad of ionizing radiation.

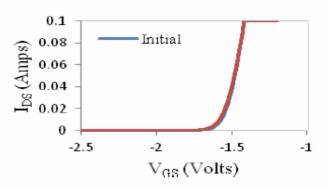


Fig. 6. Nitronex 25015 HEMT irradiate with 5 x 1014 neutrons (1 MeV equivalent). Little change is observed in the response.

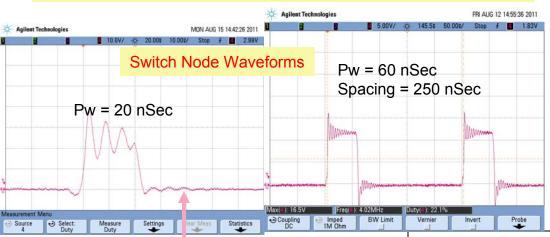
TABLE III Radiation Testing Matrix for GaN Devices

| | Ir | EPC radiated | 1015 C with 10 | | ns |
|---------------|--|---|-------------------|-----------|----|
| $I_{D}(Amps)$ | 0.10 0.08 0.06 0.04 0.02 0.00 | Before irradic After irradicti 1 week annea | ion | 1.5 s) | 2 |

Fig. 8. EPC 1015 HEMT before and after 1015 protons/cm2. During exposure VDS = 24V with a 1 kOhm resistor current limiting the channel to 24 mA. The device was "clocked" with a VGS = 4 V at a 1 kHz frequency

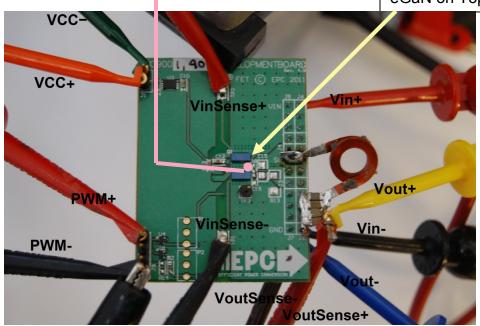
| | | | Neutron | Proton |
|----------|---------|----------|----------------------|----------------------|
| Company | Device | 60Co | Fluence | Fluence |
| | | | (cm ⁻²) | (cm ⁻²) |
| Nitronex | 25015 | 17.4Mrad | 5 x 10 ¹⁴ | 1 x 10 ¹⁵ |
| Cree | 40010 | | 5 x 10 ¹⁴ | 1 x 10 ¹⁵ |
| Eudyna | EGNB010 | 43 Mrad | 5 x 10 ¹⁴ | 1 x 10 ¹⁵ |
| EPC | EPC1015 | 64 Mrad | | 1 x 49 ¹⁵ |

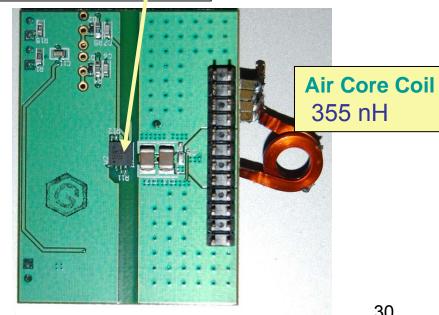
eGaN with discrete & LM5113 Driver

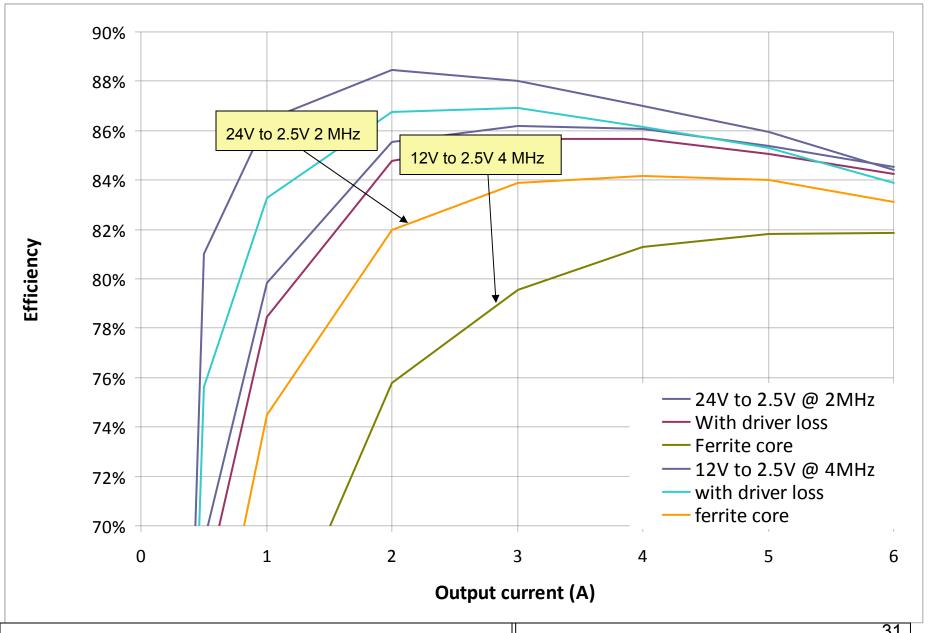




National eGaN Driver LM5113 on Bottom eGaN on Top side









Year 2000 **Zero I**ron **P**ower **S**upply

S. Mos Sanderm: NIKHEF



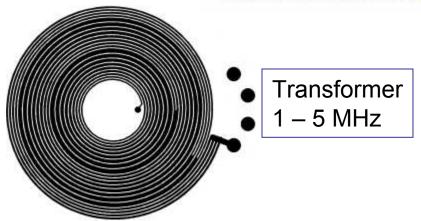
Figure 2 size of the converter (111x60x29mm, without connector and screws)

Vin = 18 V

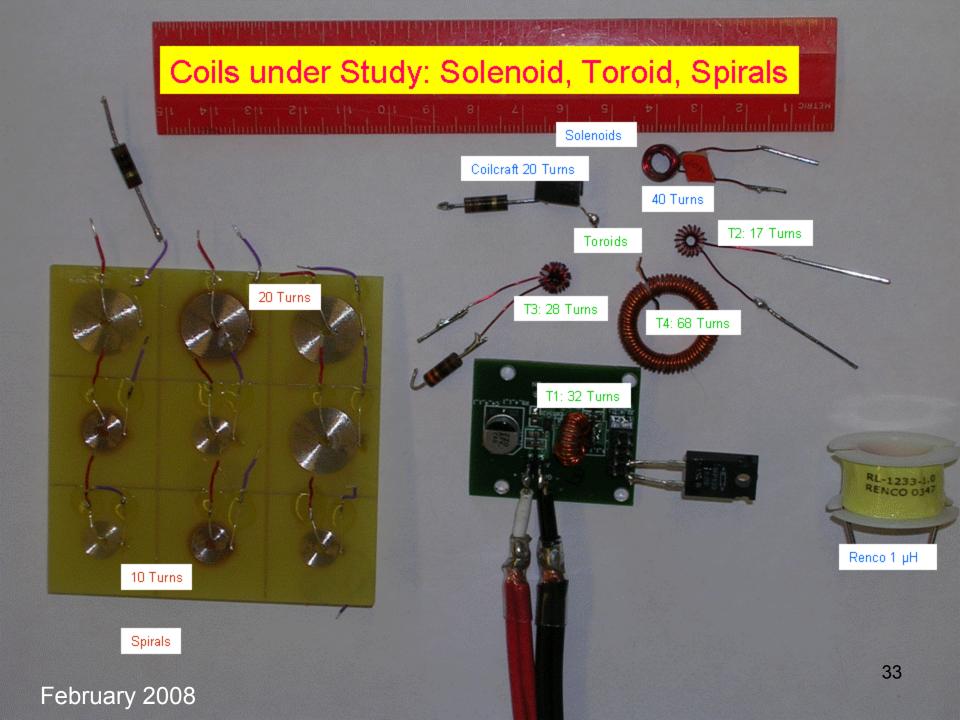
Vout = 5 V

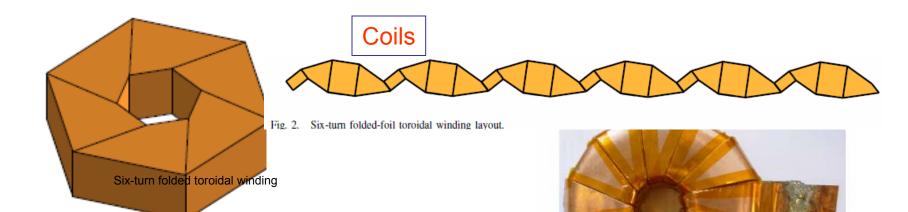
Pout = 2.5 W

Efficiency = 76%









Nigam & Sullivan: Multi-Layer Folded High-Frequency Toroidal Inductor Windings IEEE Applied Power Electronics Conference, Feb. 2008, pp. 682–688

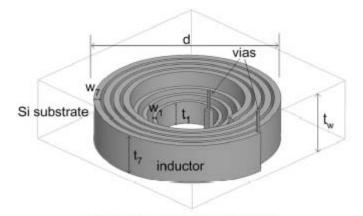


Fig. 4: Schematic 3-D view of TSECPI.

TABLE 1. WINDING DIMENSIONS FOR TSECPI

| Turn No. (from center) | 1 | 2 | 3 | 4-7 |
|------------------------|-----|-----|-----|-----|
| Winding Width (µm) | 16 | 18 | 20 | 30 |
| Winding Depth (µm) | 107 | 121 | 133 | 200 |

RF air-core solenoid under test with aluminum shield. The volume increase by a factor 9 is due to the necessity of reducing the noise emission without affecting the inductance value.

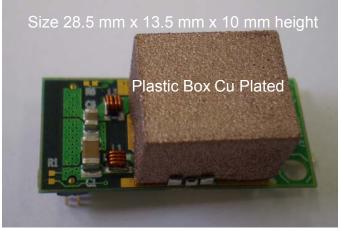
Fig. 6. Photograph of prototype.

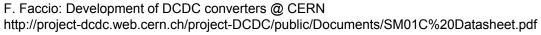
3-D image of a 150 nH PCB air-core toroid

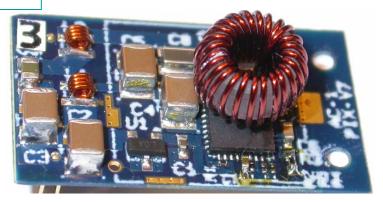
X. Fang et al "A New Embedded Inductor for ZVS DC-DC Converter Applications" Proceedings of the 2012 24th International Symposium on Power Semiconductor Devices and ICs 3-7 June 2012 - Bruges, Belgium S. Orlan

S. Orlando: Optimization of Shielded PCB Air-Core Toroids for High-Efficie DC Converters

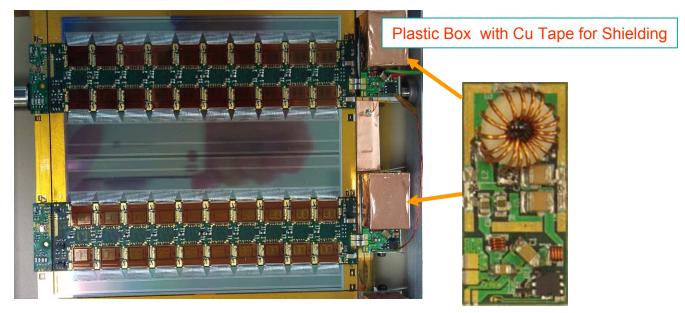
Converters with Toroid



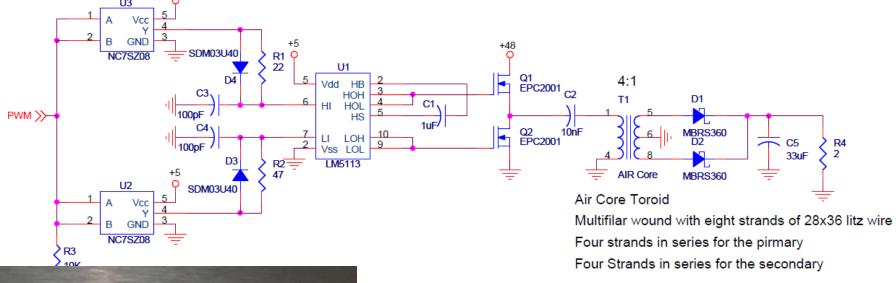




Katja Klein: DC-DC Converter Development for the CMS Pixel Upgrade https://indico.cern.ch/conferenceDisplay.py?confld=127662

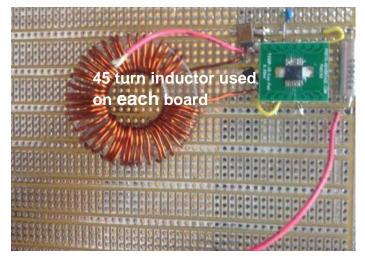


ATLAS Stavelet Update: Upgrade- Peter Phillips









Mu2e: Max Puidak DC-DC Step-Down Converters for Power Distribution.

Current Prototype Sept 24, 2012

GaN Products

GaN Target Markets

Applications of 600 V GaN Devices

- 1. AC to 380 V with Power Factor Correction (PFC)
- 2. 380 V 48 V Isolated converter
- 3. Motor Drive PWM

15 KHz is audible100 KHz is not audible & 5% higher Efficiency

Applications of < 200 V GaN Devices

- 1. 48 V to 1-12 V Converters. Smaller size compare to Silicon
- 2. 12 V to 1 V Point of Load regulator
- 3. Power Supply on a chip High Frequency operation
- 4. Wireless Power Battery Chargers

Enhancement Mode: Can make low voltage devices

Depletion mode: Can't make low voltage devices because

the Cascode does not work

GaN Company: EPC

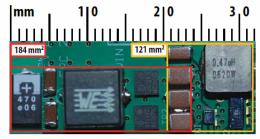
PRODUCT BRIEF

no efficiency penalty.

eGaN FETs Save Space

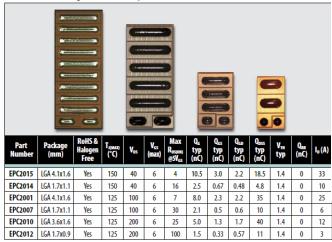
By combining the smaller-size eGaN FETs and their ability to efficiently operate at much higher frequencies, point-of-load (POL) converters can be made smaller and realize higher transient response capability. In this example the eGaN FET-based system is 34% smaller (184 mm² vs. 121 mm²) and operates at 800 kHz with

eGaN® FET Low Voltage Family



Size comparison between 300 kHz MOSFET buck (Red) and 800 kHz eGan FET buck (Orange)

eGaN FET Low Voltage Product Family





Purchasing eGaN FET Products

EPC Products are distributed exclusively through Digi-Key.



eGaN is a registered trademark of Efficient Power Conversion Corporation, Inc.

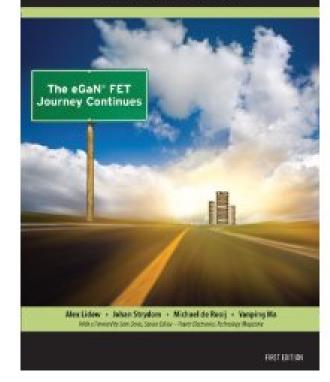
Development Boards

| Part Number | Description | V _{DS} (max) | I₀ (max RMS) | Featured Product | Schematic | Gerber | Bill of Materials |
|----------------|-------------------------|--------------------------|-----------------|---------------------|-----------|--------|----------------------|
| EPC9001 | Half Bridge Plus Driver | 40 | 15 | EPC2015 | Yes | Yes | Yes |
| EPC9002 | Half Bridge Plus Driver | 100 | 10 | EPC2001 | Yes | Yes | Yes |
| EPC9003 | Half Bridge Plus Driver | 200 | 5 | EPC2010 | Yes | Yes | Yes |
| EPC9004 | Half Bridge Plus Driver | 200 | 3 | EPC2012 | Yes | Yes | Yes |
| EPC9005 | Half Bridge Plus Driver | 40 | 7 | EPC2014 | Yes | Yes | Yes |
| EPC9006 | Half Bridge Plus Driver | 100 | 5 | EPC2007 | Yes | Yes | Yes |

Demo Circuits

| Part Number | Description | V _{IN} | V _{out} | l _{out} | Featured Product | Schematic | Gerber | Bill of Materials |
|----------------|---------------------------------|-----------------|------------------|------------------|---------------------|-----------|--------|----------------------|
| EPC9101 | 19 V to 1.2 V Buck Converter | 8V-19V | 1.2V | 18 A | EPC2015/ EPC2014 | Yes | Yes | Yes |
| EPC9102 | 48 V to 12 V Brick Converter | 36 V -60 V | 12 V | 17 A | EPC2001 | Yes | Yes | Yes |

GaN Transistors for Efficient Power Conversion

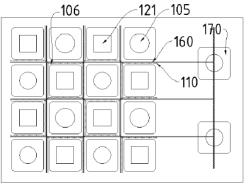


eGaN® FETs for Space Applications

Radiation Tolerant Enhancement Mode Gallium Nitride (eGaN®) FET Characteristics

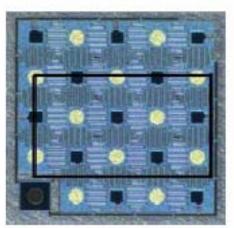
Sold @ Amazon.com

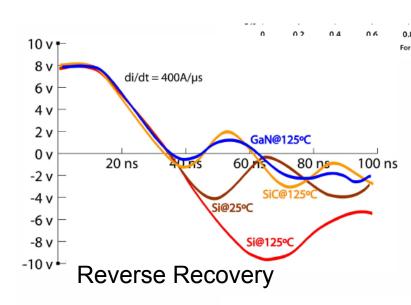
GaN Company: GaN Systems

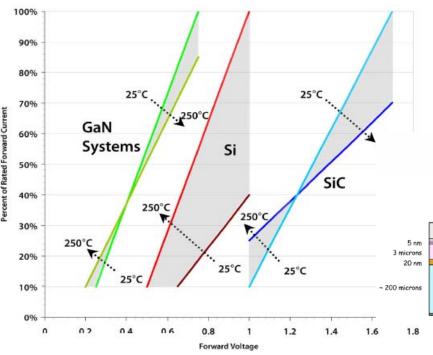


Island Technology

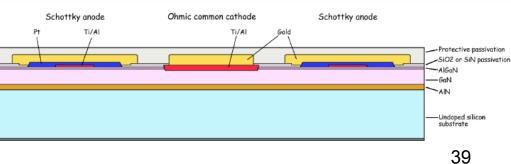
2mm x 2mm 1200 V 24 A







The low forward voltage of our first devices is due to the dual metal Schottky diode arrangement incorporated in our designs

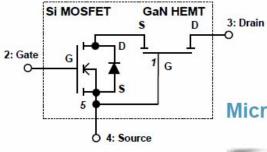


GaN Company: MicroGan

MicroGaN 600V N-OFF Switch



 $C_{\text{oss}} = 42 \text{pF}$ $R_{\text{DSon}} = 320 \text{m}\Omega$



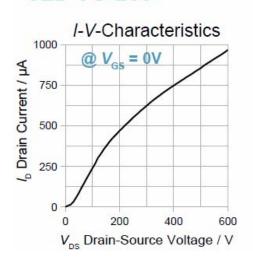
MicroGaN 600V Schottky Barrier Diode

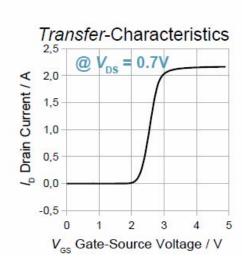
 $Q_{\rm D} = 18.6 {\rm nC}$

 $V_{\rm b} = 0.3 \rm{V}$

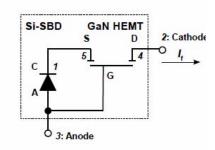
 $I_{\rm F} = 4A$









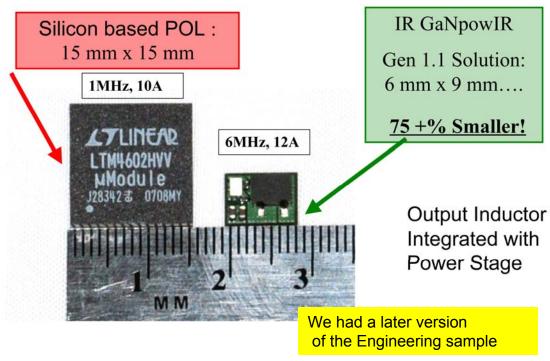


GaN Company: International Rectifier

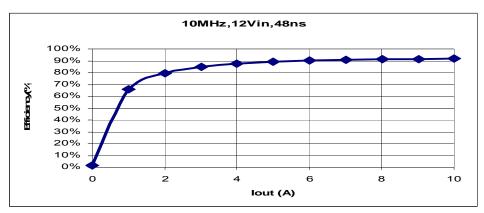
GaN on Si



6 times Higher Frequency over Si Solution with similar efficiency!



Part Number iP2010TRPBF Vin + 7 – 13.20.6 (V)Vout Range Vout = 0.6 – 5.5 V Iout = 20 A. Frequency 250 kHz – 3 MHz Size = 7.7 x 6.5mm LGA - 5.530250 – 3,000



GaN Company: Transphorm

Company backed by \$63 million from Quantum Strategic Partners Ltd. and existing venture investors Kleiner Perkins, Google Ventures, Foundation Capital, and Lux Capital

600-V GaN power components delivered

Power transistor startup Transphorm Inc. has produced gallium-nitride on silicon components with a breakdown voltage of 600-V.

The company had previously announced a range of GaN power diodes. The company has added more diodes and power transistors to its range. The breakdown voltage of 600-V means that the improved power efficiency of GaN can be applied to applications that operate direct from mains electricity...

The following 600-V breakdown products are available for sale as evaluation samples through the Transphorm website but only to "approved" customers: TP\$30xxPK series

GaN diode with 2, 4, and 6-amp current, in a TO-220 package; TPH3006PS 180 mohm GaN transistor in TO-220 package; TPT3044M three-phase GaN module and related inverter application board TDMD2000E0I

Full story: http://bit.ly/RCZ1UW

Transphorm Inc. today announced the JEDEC qualification of the company's TPH2006PS, GaN HEMT on SiC substrate, making it the industry's first qualified 600V HEMT device. The TPH2006PS, based on its patented, high-performance EZ-GaN™ technology, combines low switching and conduction losses resulting in reduced energy loss of up to 50% compared to conventional silicon-based power conversion designs, today. The TO-220-packaged device features RDS(on) of 150 mΩ, Qrr of 42 nC and high frequency switching capability that enables compact, lower cost systems September 13, 2012

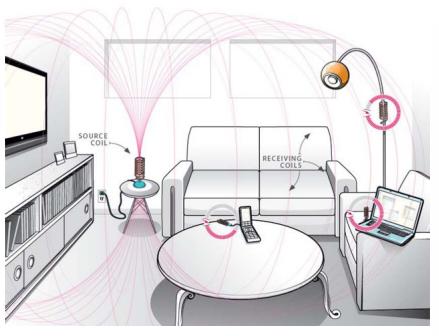
Transphorm awarded for advancing GaN power technology

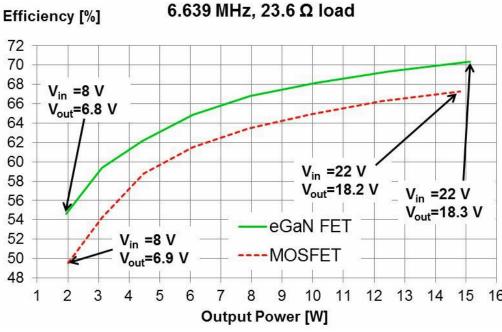
Sep 19, 2012

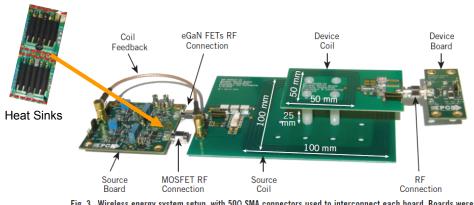
The innovator of gallium nitride design and process technologies has been honoured for enabling implementation of highly-efficient power conversion systems

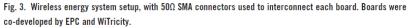
Transphorm has been selected by the World Economic Forum as a 2013 Technology Pioneer, citing the company's innovations in GaN technology

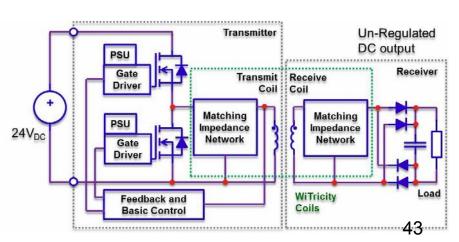
Wireless Power



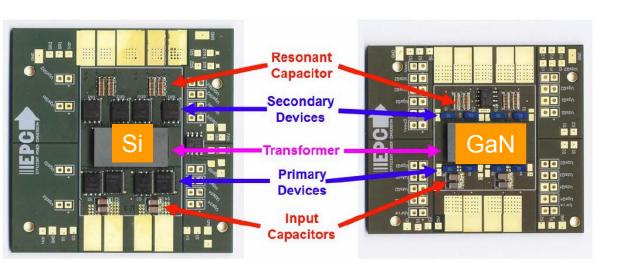








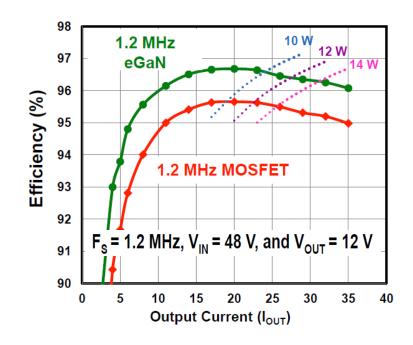
GaN Vs MOSFET Resonant Converters



Converters

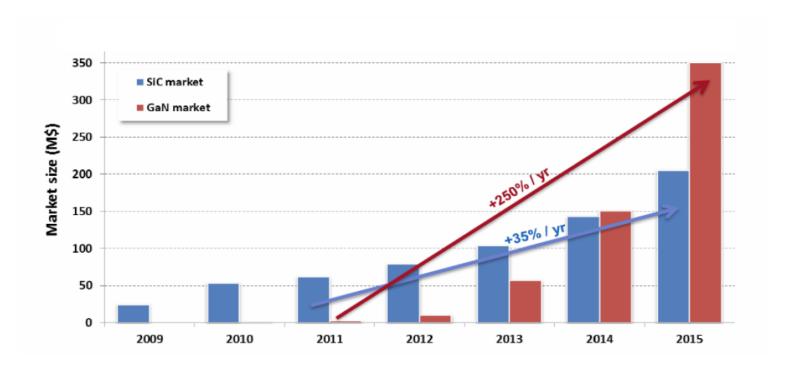
Hard Switch: ???

Resonant: ?????



Loss Power
Output limited by Heat Removal

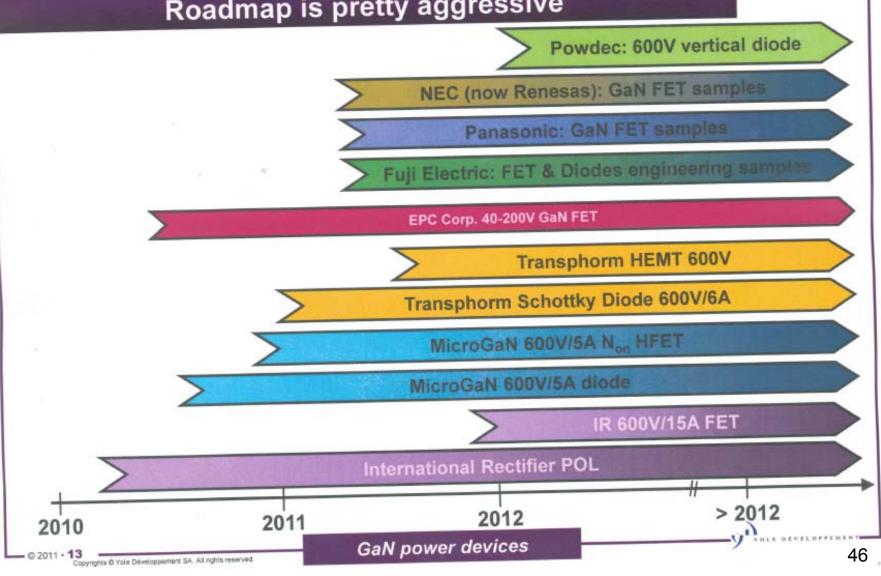
GaN Market Projection



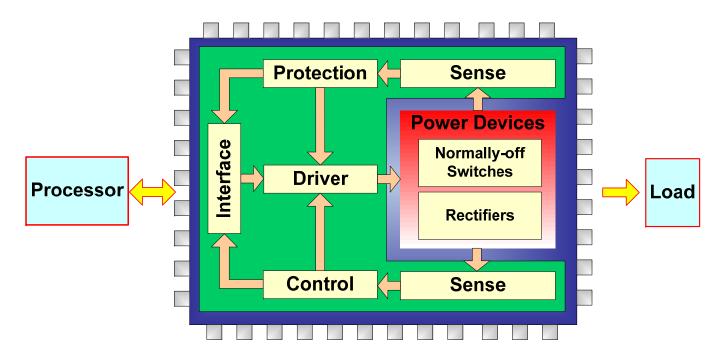
Total = \$350M for GaN in 2015

Source: Yole Development

2010 was the start for GaN power products. Roadmap is pretty aggressive

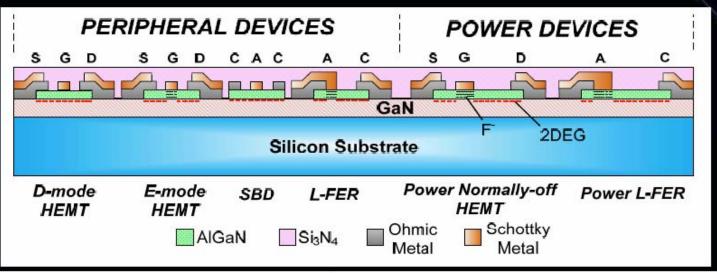


Implementation of GaN power modules



- Multi-chip modules: GaN(power)+Si CMOS (peripheral circuits)
 - → quick design turn-around, development is underway
 - → operating temperature limit set by Si
- All-GaN single-chip solution: long development time for GaN digital/analog ICs, wide temperature range

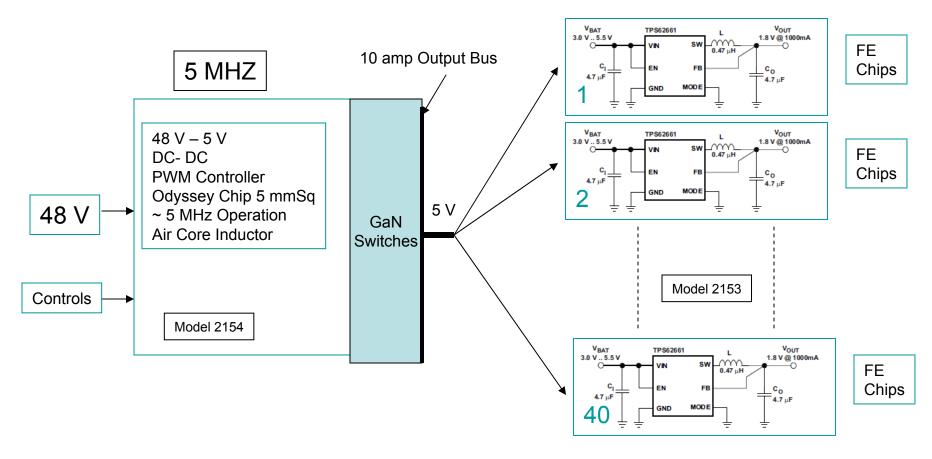
GaN Smart Power Technology Platform



| Power Devices | Smart Part | | | |
|--|--------------------------|------------|--|--|
| ❖ Normally-off HEMT ∴ Leteral Field Effect | Digital: | Analog: | | |
| Lateral Field-Effect Rectifier (L-FER) | Direct-coupled FET logic | Protection | | |
| | (DCFL) | | | |

2 Step Power Converter Distribution



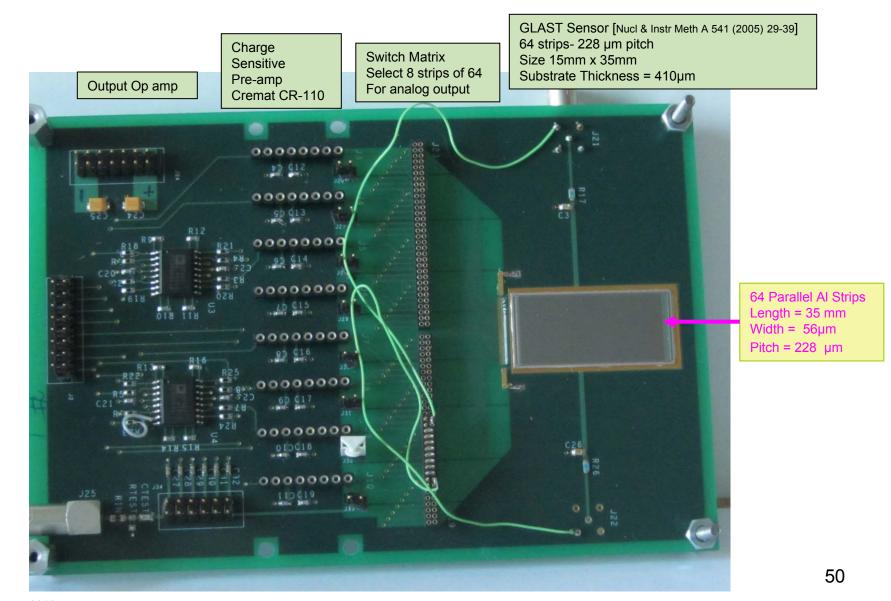


Standard 6 BGA csp package 0.4 mm pitch Air Core Inductor

48V – 5V 10 amps

 $5V - \sim 1.2V \ 1 \ amp: 40 \ Loads$

Test Silicon Strip Detector with Analog Readout



Summary/ Conclusions

- Portable Devices will have big impact on Physics Power Distribution
- First Stage: Single Die with air core Inductor on Die/PCB
- Second Stage: MCM with PWM, Power Switch with Driver & Inductor
- Power Delivery 380 V DC from Power Cavern to isolated BUCK Converter & then 48 V into Detector
- Improve power efficiency Glaciers are melting > Good / Bad ?

Greenland. What a view & Swimming next to Icebergs is Great







Recent New York Times Report Soon no summer ice Glacier melting? Expose minerals



Working on Physics Power Supply Is not considered Glamorous

Top of the World is Cool but lonely!
Let us keep it cool with highly efficient PS
Swimming is Great at the North Pole

On the way to North Pole 2001

END

http://shaktipower.sites.yale.edu/